# Memory FRAM

# 128K (16 K × 8) Bit SPI

# **MB85RS128A**

# DESCRIPTION

MB85RS128A is a FRAM (Ferroelectric Random Access Memory) chip in a configuration of 16,384 words  $\times$  8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells.

MB85RS128A adopts the Serial Peripheral Interface (SPI).

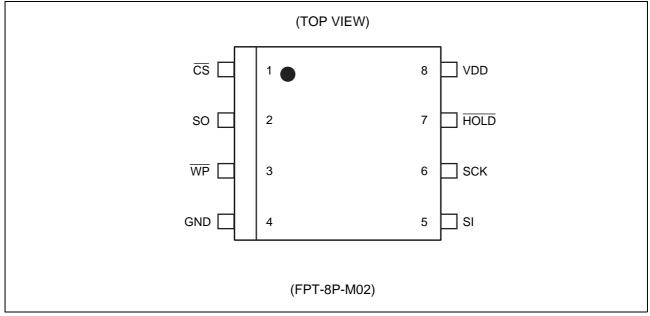
The MB85RS128A is able to retain data without using a back-up battery, as is needed for SRAM. The memory cells used in the MB85RS128A can be used for 10<sup>12</sup> read/write operations, which is a significant improvement over the number of read and write operations supported by Flash memory and E<sup>2</sup>PROM. MB85RS128A does not take long time to write data like Flash memories or E<sup>2</sup>PROM, and MB85RS128A takes no wait time.

# ■ FEATURES

<ul> <li>Bit configuration</li> </ul>	: 16,384 words $\times$ 8 bits
Serial Peripheral Interface	: SPI (Serial Peripheral Interface)
	Correspondent to SPI mode 0 (0, 0) and mode 3 (1, 1)
<ul> <li>Operating frequency</li> </ul>	: 25 MHz (Max)
<ul> <li>High endurance</li> </ul>	: 10 <sup>12</sup> times / byte
<ul> <li>Data retention</li> </ul>	: 10 years (+55 °C), 55 years (+35 °C)
<ul> <li>Operating power supply voltage</li> </ul>	: 3.0 V to 3.6 V
<ul> <li>Low power consumption</li> </ul>	: Operating power supply current 5 mA (Typ @25 MHz)
	Standby current 9 μA (Typ)
Operation ambient temperature ra	ange : - 40 °C to + 85 °C
Package	: 8-pin plastic SOP (FPT-8P-M02)
	RoHS compliant



# ■ PIN ASSIGNMENT

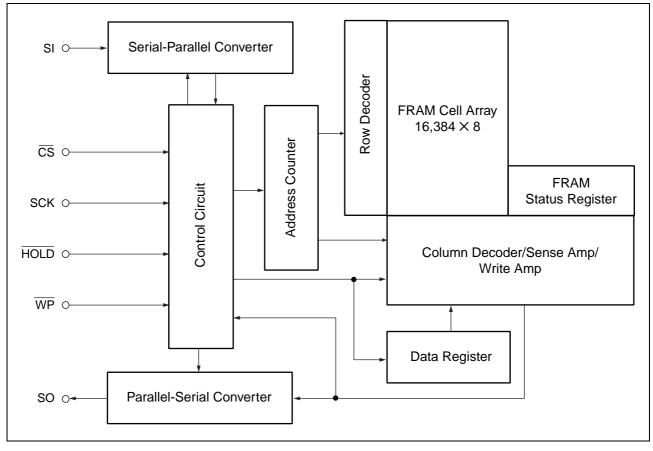


# ■ PIN FUNCTIONAL DESCRIPTIONS

Pin No.	Pin Name	Functional description
1	CS	Chip Select pin This is an input pin to make chip select. When $\overline{CS}$ is the "H" level, device is in deselect (standby) status and SO becomes High-Z. Inputs from other pins are ignored at this time. When $\overline{CS}$ is the "L" level, device is in select (active) status. $\overline{CS}$ has to be the "L" level before inputting op-code.
3	WP	Write Protect pin This is a pin to control writing to a status register. The writing of status register (see "■STATUS REGISTER") is protected in related with WP and WPEN. See "■WRITING PROTECT" for detail.
7	HOLD	Hold pin This pin is used to interrupt serial input/output without making chip deselect. When HOLD is the "L" level, hold operation is activated, SO becomes High-Z, and SCK and SI become don't care. While the hold operation, $\overline{CS}$ shall be retained the "L" level.
6	SCK	Serial Clock pin This is a clock input pin to input/output serial data. SI is loaded synchronously to a rising edge, SO is output synchronously to a falling edge.
5	SI	Serial Data Input pin This is an input pin of serial data. This inputs op-code, address, and writing data.
2	SO	Serial Data Output pin This is an output pin of serial data. Reading data of FRAM memory cell array and status register are output. This is High-Z during standby.
8	VDD	Supply Voltage pin
4	GND	Ground pin

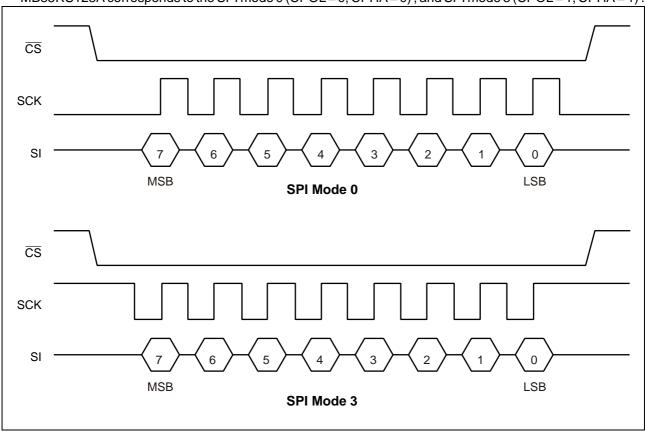
# **MB85RS128A**

#### BLOCK DIAGRAM





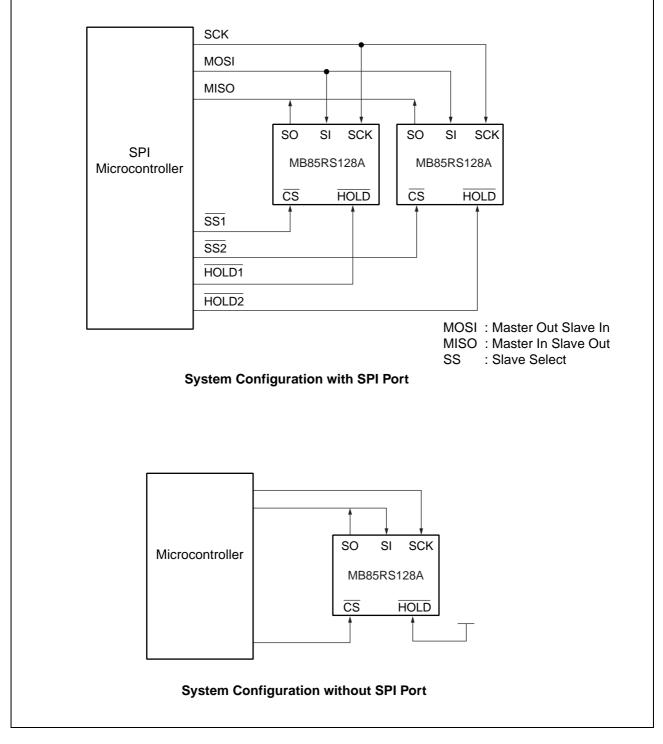
# SPI MODE



MB85RS128A corresponds to the SPI mode 0 (CPOL=0, CPHA=0), and SPI mode 3 (CPOL=1, CPHA=1).

# SERIAL PERIPHERAL INTERFACE (SPI)

MB85RS128A works as a slave of SPI. More than 2 devices can be connected by using microcontroller equipped with SPI port. By using a microcontroller not equipped with SPI port, SI and SO can be bus connected to use.



# ■ STATUS REGISTER

Bit No.	Bit Name	Function
7	WPEN	Status Register Write Protect This is a bit composed of nonvolatile memories (FRAM). WPEN protects writing to a status register (refer to "■ WRITING PROTECT") relating with WP input. Writing with the WRSR command and reading with the RDSR command are possible.
6 to 4	_	Not Used Bits These are bits composed of nonvolatile memories, writing with the WRSR command is possible, and "000" is written before shipment. These bits are not used but they are read with the RDSR command.
3	BP1	Block Protect This is a bit composed of nonvolatile memory. This defines size of write
2	BP0	protect block for the WRITE command (refer to "■ BLOCK PROTECT"). Writing with the WRSR command and reading with the RDSR command are possible.
1	WEL	Write Enable Latch         This indicates an FRAM Array and status register are writable. The         WREN command is for setting, and the WRDI command is for resetting.         With the RDSR command, reading is possible but writing is not possible         with the WRSR command. WEL is reset after the following operations.         After power ON.         After WRDI command recognition.         At the rising edge of CS after WRSR command recognition.         At the rising edge of CS after WRITE command recognition.
0	0	This is a bit fixed to "0".

# ■ OP-CODE

MB85RS128A accepts 6 kinds of command specified in op-code. Op-code is a code composed of 8 bits shown in the table below. Do not input invalid codes other than those codes. If  $\overline{CS}$  is risen while inputting op-code, the command are not performed.

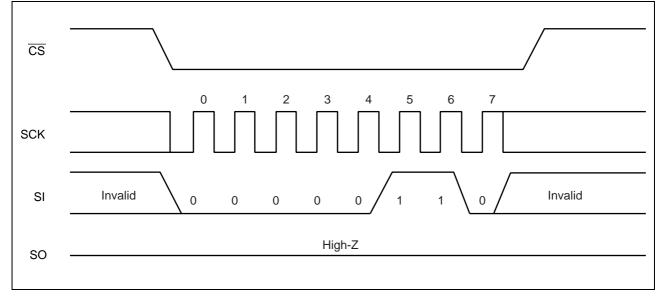
Name	Description	Op-code
WREN	Set Write Enable Latch	0000 0110в
WRDI	Reset Write Enable Latch	0000 0100в
RDSR	Read Status Register	0000 0101в
WRSR	Write Status Register	0000 0001в
READ	Read Memory Code	0000 0011в
WRITE	Write Memory Code	0000 0010в



# ■ COMMAND

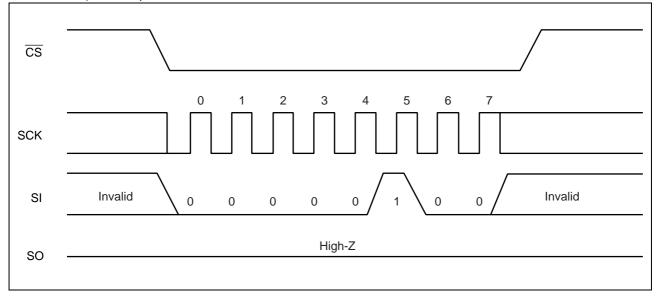
#### • WREN

The WREN command sets WEL (Write Enable Latch) . WEL shall be set with the WREN command before writing operation (WRSR command and WRITE command) .



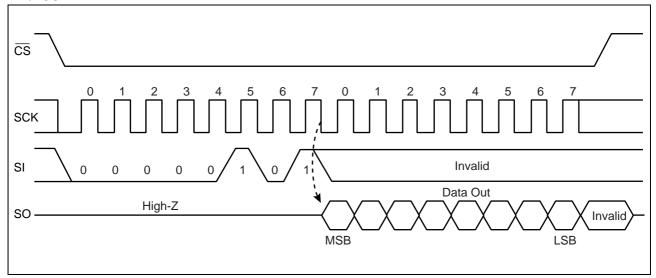
#### • WRDI

The WRDI command resets WEL (Write Enable Latch) . Writing operation (WRITE command and WRSR command) are not performed when WEL is reset.



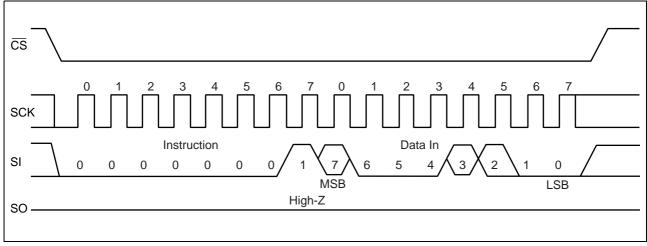
#### • RDSR

The RDSR command reads status register data. After op-code of RDSR is input to SI, 8-cycle clock is input to SCK. The SI value is invalid during this time. SO is output synchronously to a falling edge of SCK. In the RDSR command, repeated reading of status register is enabled by sending SCK continuously before rising of  $\overline{CS}$ .



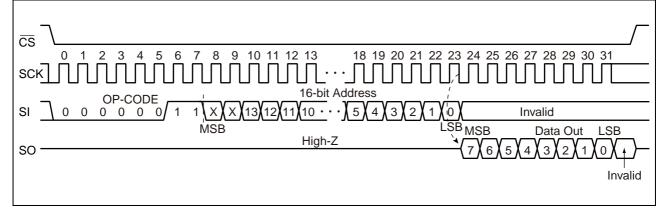
#### • WRSR

The WRSR command writes data to the nonvolatile memory bit of status register. After performing WRSR op-code to a SI pin, 8 bits writing data is input. WEL (Write Enable Latch) is not able to be written with WRSR command. A SI value correspondent to bit 1 is ignored. Bit 0 of the status register is fixed to "0" and cannot be written. The SI value corresponding to bit 0 is ignored. The WP signal level shall be fixed before performing the WRSR command, and do not change the WP signal level until the end of command sequence.



#### • READ

The READ command reads FRAM memory cell array data. Arbitrary 16 bits address and op-code of READ are input to SI. The 2-bit upper address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When  $\overline{CS}$  is risen, the READ command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before  $\overline{CS}$  rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



#### • WRITE

The WRITE command writes data to FRAM memory cell array. WRITE op-code, arbitrary 16 bits of address and 8 bits of writing data are input to SI. The 2-bit upper address bit is invalid. When 8 bits of writing data is input, data is written to FRAM memory cell array. Risen  $\overline{CS}$  will terminate the WRITE command. However, if you continue sending the writing data for 8 bits each before  $\overline{CS}$  rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, it rolls over to the starting address, and writing cycle keeps on infinitely.

cs	
00	0 1 2 3 4 5 6 7 8 9 10 11 12 13 18 19 20 21 22 23 24 25 26 27 28 29 30 31
SC	
SI	1000001 (XX) (13) (12) (1) (10) (X) (X) (13) (12) (1) (10) (X) (X) (X) (X) (X) (X) (X) (X) (X) (X
	MSB LSB MSB LSB High-Z
SO	Tingn-Z

# BLOCK PROTECT

Writing protect block for WRITE command is configured by the value of BP0 and BP1 in the status register.

BP1	BP0	Protected Block		
0	0	None		
0	1	3000н to 3FFFн (upper 1/4)		
1	0	2000н to 3FFFн (upper 1/2)		
1	1	0000н to 3FFFн (all)		

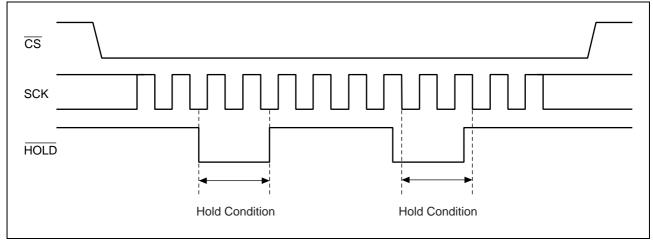
# WRITING PROTECT

Writing operation of the WRITE command and the WRSR command are protected with the value of WEL, WPEN,  $\overline{WP}$  as shown in the table.

WEL	WPEN	WP	Protected Blocks Unprotected Blocks Sta		Status Register
0	Х	Х	Protected	Protected	Protected
1	0	Х	Protected	Unprotected	Unprotected
1	1	0	Protected	Unprotected	Protected
1	1	1	Protected	Unprotected	Unprotected

# ■ HOLD OPERATION

Hold status is retained without aborting a command if  $\overline{HOLD}$  is the "L" level while  $\overline{CS}$  is the "L" level. The timing for starting and ending hold status depends on the SCK to be the "H" level or the "L" level when a HOLD pin input is transited to the hold condition as shown in the diagram below. In case the  $\overline{HOLD}$  pin transited to "L" level when SCK is "L" level, return the  $\overline{HOLD}$  pin to "H" level at SCK being "L" level. In the same manner, in case the  $\overline{HOLD}$  pin transited to "L" level when SCK is "L" level, return the  $\overline{HOLD}$  pin to "H" level, return the  $\overline{HOLD}$  pin to "H" level at SCK being "H" level. Arbitrary command operation is interrupted in hold status, SCK and SI inputs become don't care. And, SO becomes High-Z while reading command (RDSR, READ). If  $\overline{CS}$  is rising during hold status, a command is aborted. In case the command is aborted before its recognition, WEL holds the value before transition to HOLD status.



# ■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rat	Unit	
		Min	Max	Unit
Power supply voltage*	Vdd	- 0.5	+ 4.0	V
Input voltage*	VIN	- 0.5	Vdd + 0.5	V
Output voltage*	Vout	- 0.5	Vdd + 0.5	V
Operation ambient temperature	TA	- 40	+ 85	°C
Storage temperature	Tstg	- 55	+ 125	°C

\*:These parameters are based on the condition that  $V_{\text{SS}}$  is 0 V.

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

# RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit		
		Min	Тур	Max	Onit
Power supply voltage*	Vdd	3.0	3.3	3.6	V
Input high voltage*	Vih	$V_{DD}  imes 0.8$	—	Vdd + 0.5	V
Input low voltage*	VIL	- 0.5	—	+ 0.6	V
Operation ambient temperature	TA	- 40		+ 85	°C

\*: These parameters are based on the condition that Vss is 0 V.

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their representatives beforehand.

# ■ ELECTRICAL CHARACTERISTICS

# 1. DC Characteristics

#### (within recommended operating conditions)

(						
Parameter	Cumb al	Condition	Value			Unit
Farameter	Symbol		Min	Тур	Max	Unit
Input leakage current*1	<b>I</b> u	$V_{IN} = 0 V \text{ to } V_{DD}$			10	μΑ
Output leakage current*2	<b>I</b> lo	$V_{OUT} = 0 V to V_{DD}$	_		10	μΑ
Operating power supply current	ldd	SCK = 25 MHz	_	5	10	mA
Standby current	Іѕв	All inputs $V_{SS}$ or SCK = SI = $\overline{CS}$ = $V_{DD}$	_	9	50	μΑ
Output high voltage	Vон	Iон = −2 mA	$V_{\text{DD}} \times 0.8$		_	V
Output low voltage	Vol	IoL = 2 mA			0.4	V

\*1 : Applicable pin :  $\overline{CS}$ ,  $\overline{WP}$ ,  $\overline{HOLD}$ , SCK, SI

\*2 : Applicable pin : SO

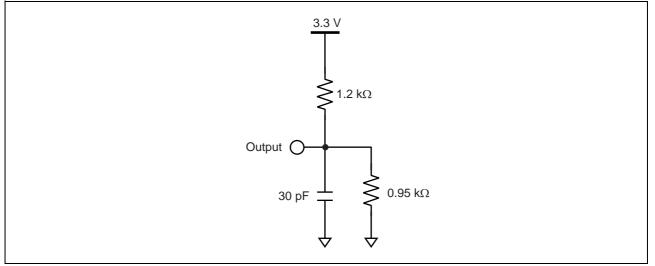
# 2. AC Characteristics

Deremeter	Symbol	V	Value		
Parameter	Symbol	Min	Max	– Unit	
SCK clock frequency	fcк	0	25	MHz	
Clock high time	tсн	20		ns	
Clock low time	tc∟	20		ns	
Chip select set up time	tcsu	10		ns	
Chip select hold time	tсsн	10		ns	
Output disable time	top		20	ns	
Output data valid time	todv		18	ns	
Output hold time	tон	0		ns	
Deselect time	to	60		ns	
Data rising time	tR		50	ns	
Data falling time	t⊧		50	ns	
Data set up time	tsu	5		ns	
Data hold time	tн	5		ns	
HOLD set up time	tнs	10		ns	
HOLD hold time	tнн	10		ns	
HOLD output floating time	tнz		20	ns	
HOLD output active time	t∟z		20	ns	

### **AC Test Condition**

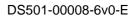
Power supply voltage: 3.0 V to 3.6 VOperation ambient temperature :- 40 °C toInput voltage magnitude: 0.3 V to 2.7 VInput rising time: 5 nsInput falling time: 5 nsInput judge level: VbD/2Output judge level: VbD/2

# AC Load Equivalent Circuit



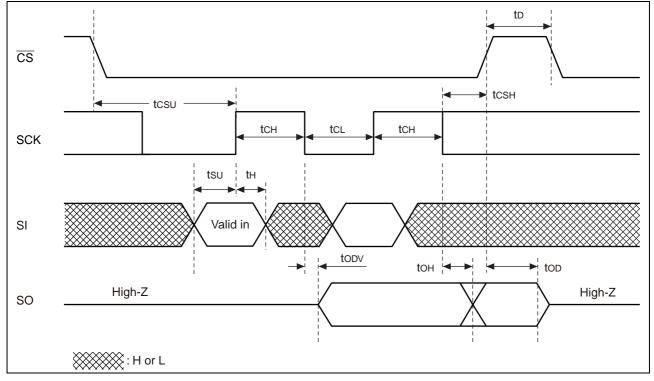
# 3. Pin Capacitance

Parameter	Symbol Conditions		Va	Unit	
	Symbol	Conditions	Min	Max	Onit
Output capacitance	Co	$V_{DD} = V_{IN} = V_{OUT} = 0 V,$		10	pF
Input capacitance	Cı	$f = 1 \text{ MHz}, T_A = +25 \ ^{\circ}\text{C}$		10	pF

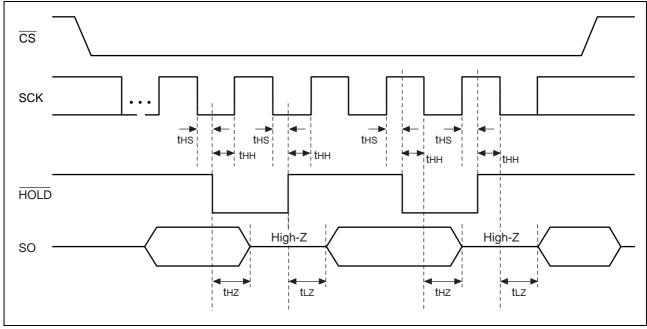


#### ■ TIMING DIAGRAM

#### Serial Data Timing

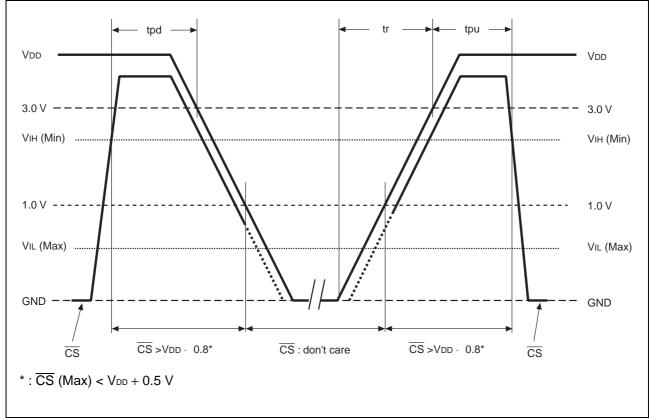


#### • Hold Timing



# POWER ON/OFF SEQUENCE

If  $V_{DD}$  falls down below 2.0 V,  $V_{DD}$  is required to be started from 1.0 V or less to prevent malfunctions when the power is turned on again (see the figure below).



Parameter	Symbol	Va	lue	Unit
Falameter	Symbol	Min	Max	Onit
CS level hold time at power OFF	tpd	200		ns
CS level hold time at power ON	tpu	85	_	ns
Power supply rising time	tr	0.05	200	ms

If the device does not operate within the specified conditions of read cycle, write cycle or power on/off sequence, memory data can not be guaranteed.

# ■ FRAM CHARACTERISTICS

ltem	Min	Max	Unit	Parameter
Read/Write Endurance*1	10 <sup>12</sup>	_	Times/byte	Operation Ambient Temperature $T_A = +85 \ ^{\circ}C$
Data Retention*2	10	_	Years	Operation Ambient Temperature $T_A = +55 \ ^{\circ}C$
	55		reals	Operation Ambient Temperature $T_A = +35 \ ^{\circ}C$

\*1 : Total number of reading and writing defines the minimum value of endurance, as an FRAM memory operates with destructive readout mechanism.

\*2 : Minimun values define retention time of the first reading/writing data right after shipment, and these values are calculated by qualification results.

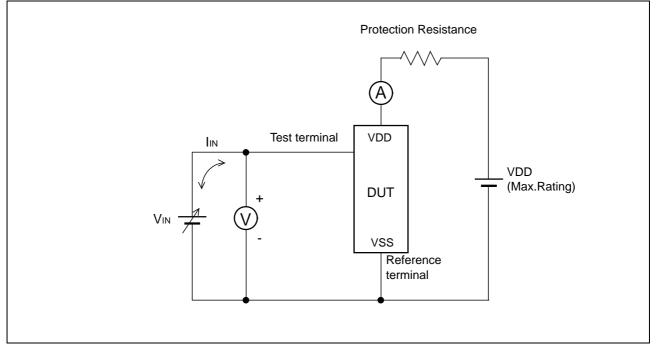
# ■ NOTE ON USE

We recommend programming of the device after reflow. Data written before reflow cannot be guaranteed.

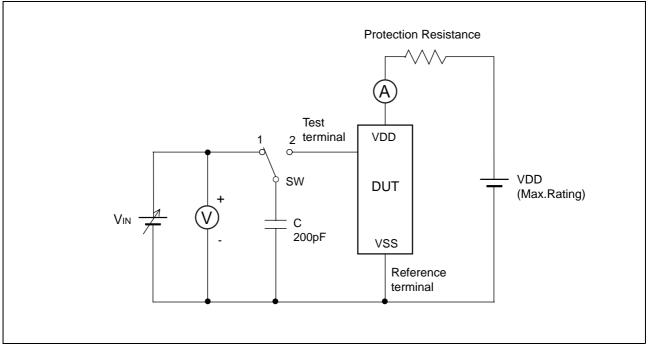
#### ■ ESD AND LATCH-UP

Test	Test DUT					
ESD HBM (Human Body Model) JESD22-A114 compliant		≥  2000 V				
ESD MM (Machine Model) JESD22-A115 compliant		≥  200 V				
ESD CDM (Charged Device Model) JESD22-C101 compliant		≥  1000 V				
Latch-Up (I-test) JESD78 compliant	MB85RS128APNF-G-JNE1					
Latch-Up (V <sub>supply</sub> overvoltage test) JESD78 compliant						
Latch-Up (Current Method) Proprietary method		≥  300 mA				
Latch-Up (C-V Method) Proprietary method						

• Current method of Latch-Up Resistance Test



Note : The voltage V<sub>IN</sub> is increased gradually and the current I<sub>IN</sub> of 300 mA at maximum shall flow. Confirm the latch up does not occur under I<sub>IN</sub> = ± 300 mA. In case the specific requirement is specified for I/O and I<sub>IN</sub> cannot be 300 mA, the voltage shall be increased to the level that meets the specific requirement. • C-V method of Latch-Up Resistance Test



Note : Charge voltage alternately switching 1 and 2 approximately 2 sec interval. This switching process is considered as one cycle.

Repeat this process 5 times. However, if the latch-up condition occurs before completing 5 times, this test must be stopped immediately.

# ■ REFLOW CONDITIONS AND FLOOR LIFE

[ JEDEC MSL ] : Moisture Sensitivity Level 3 (ISP/JEDEC J-STD-020D)

# ■ CURRENT STATUS ON CONTAINED RESTRICTED SUBSTANCES

This product complies with the regulations of REACH Regulations, EU RoHS Directive and China RoHS. Please refer to the following web site for more details of current status on contained restricted substances in our products.

http://www.fujitsu.com/global/services/microelectronics/environment/products/

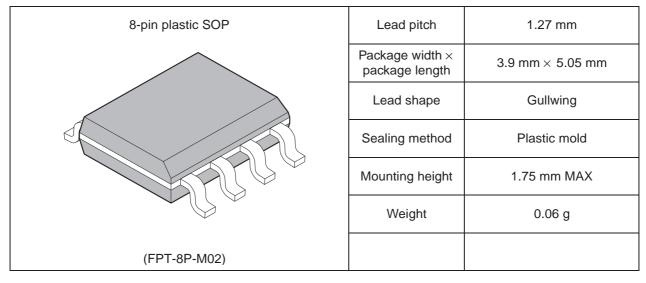
# ■ ORDERING INFORMATION

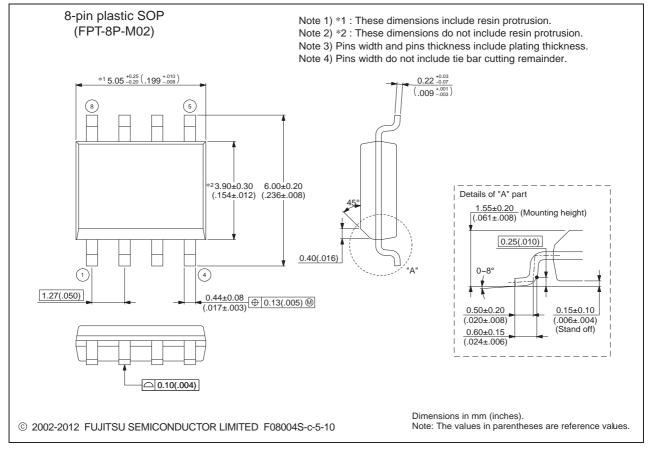
Part number	Package	Shipping form	Minimum shipping quantity
MB85RS128APNF-G-JNE1	8-pin plastic SOP (FPT-8P-M02)	Tube	*
MB85RS128APNF-G-JNERE1	8-pin plastic SOP (FPT-8P-M02)	Embossed Carrier tape	1500

\*: Please contact our sales office about minimum shipping quantity.



# PACKAGE DIMENSION

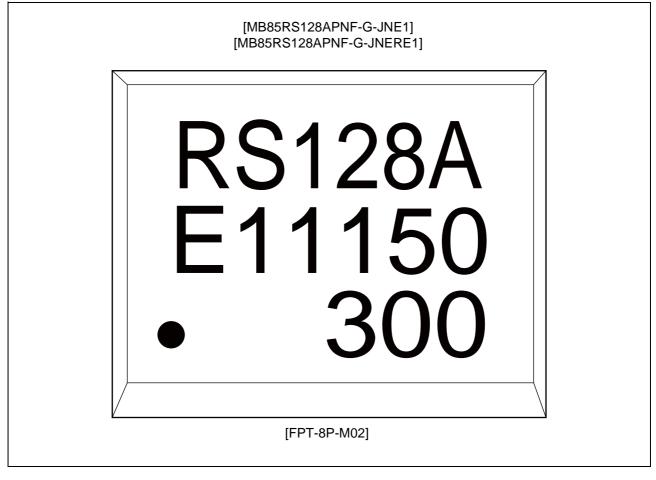




ITSU

Please check the latest package dimension at the following URL. http://edevice.fujitsu.com/package/en-search/

#### ■ MARKING



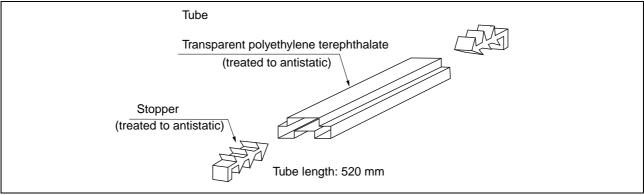


# PACKING INFORMATION

# 1. Tube

#### 1.1 Tube Dimensions

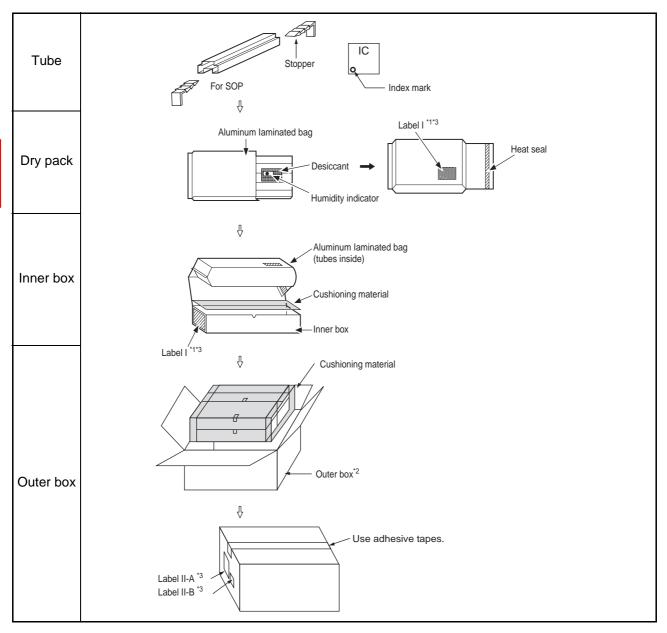
Tube/stopper shape



#### Tube cross-sections and Maximum quantity

		Ν	laximum qua	antity
Package form	Package code	pcs/ tube	pcs/inner box	pcs/outer box
SOP, 8, plastic (2)	FPT-8P-M02	95	7600	30400
©2006-2010 FUJITSU SEMICONDUCTOR LIMITED F08008-SET1-PET:FJ99L-0022-E0008-1-K-3				
t = 0.5 Transparent polyethylene terephthalate				

(Dimensions in mm)



#### 1.2 Tube Dry pack packing specifications

\*1: For a product of witch part number is suffixed with "E1", a " G (R)" marks is display to the moisture barrier bag and the inner boxes.

\*2: The space in the outer box will be filled with empty inner boxes, or cushions, etc.

\*3: Please refer to an attached sheet about the indication label.

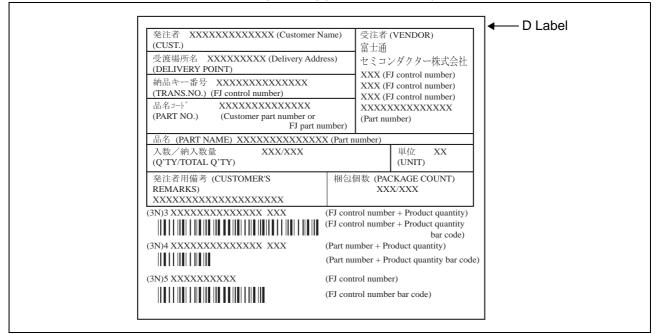
Note: The packing specifications may not be applied when the product is delivered via a distributor.

#### 1.3 Product label indicators

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]

XXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXX
(3N)2 XXXXXXXX XXXXXX (FJ control number) XXX pcs (Quantity) XXXXXXXXXXXXXX (Customer part number or FJ part number) XXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXX

Label II-A: Label on Outer box [D Label] (100mm × 100mm)



#### Label II-B: Outer boxes product indicate

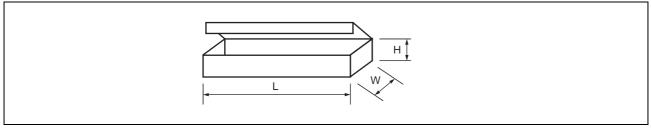
XXXXXXXXXXXXX (I	Part number)		
(Lot Number) XXXX-XXX XXXX-XXX	(Count) X箱 X箱 計	(Quantity) XXX 個 XXX 個 XXX 個	

Note: Depending on shipment state, "Label II-A" and "Label II-B" on the external boxes might not be printed.

Г

#### 1.4 Dimensions for Containers

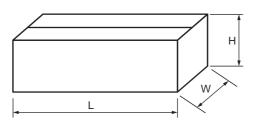
#### (1) Dimensions for inner box



L	W	Н
540	125	75

(Dimensions in mm)

#### (2) Dimensions for outer box

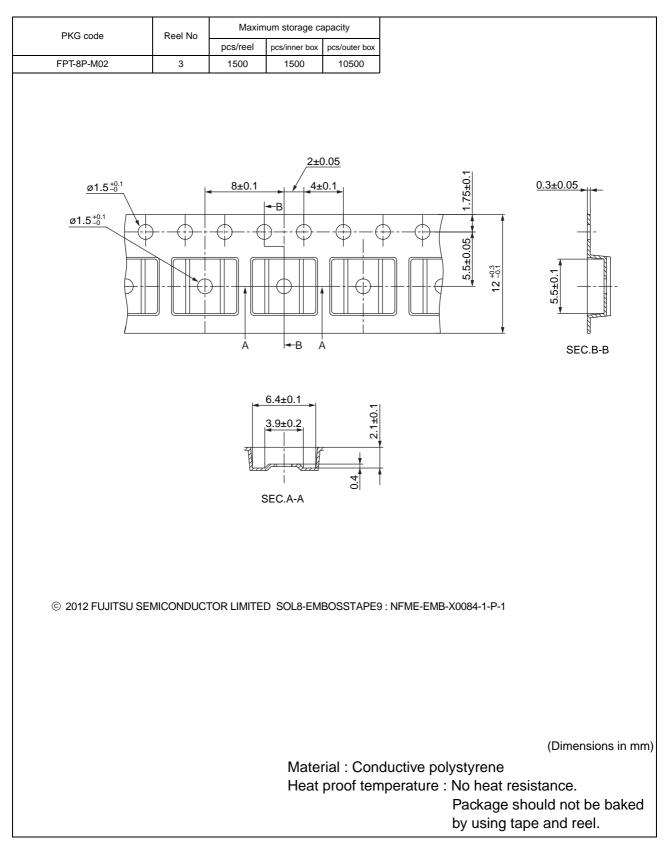


L	W	Н
565	270	180

(Dimensions in mm)

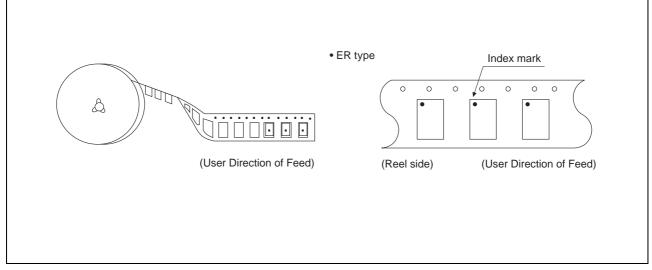
# 2. Emboss Tape

# 2.1 Tape Dimensions

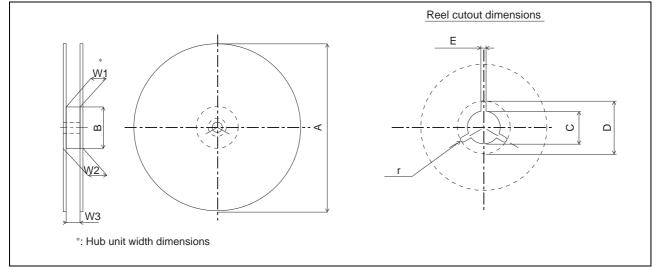


FUĬĬTSU

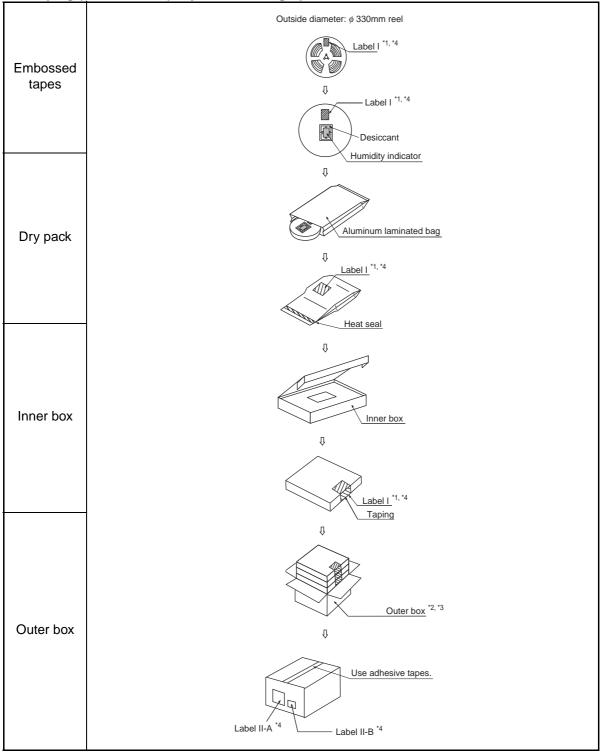
#### 2.2 IC orientation



#### 2.3 Reel dimensions



													D	imensior	ns in mm
Reel No	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
Tape width Symbol	8	1	2	1	6	2	24	3	2	4	4	56	12	16	24
A	254 ± 2	254 ± 2	330 ± 2	254 ± 2	330 ± 2	254 ± 2	330 ± 2				330	) ± 2			
В				1	00 <del>+</del> 2			100 -0	150 <sup>+2</sup>	100 +2	150 <sup>+2</sup> -0	100 +2		100 ± 2	
С						13 ±	± 0.2							13 <sup>+0.5</sup>	
D						21 ±	£ 0.8							20.5 +1 -0.2	
E								$2 \pm 0.5$					•		
W1	8.4 -0	1	2.4 +2	1	6.4 <sup>+2</sup>	24	4.4 <sup>+2</sup> -0	32	2.4 -0	44	1.4 <sup>+2</sup> -0	56.4 +2	12.4 +1	16.4 +1	24.4+0.1
W2	less than 14.4	less th	an 18.4	less th	an 22.4	less the	an 30.4	less tha	an 38.4	less tha	an 50.4	less than 62.4	less than 18.4	less than 22.4	less than 30.4
W3	7.9 ~ 10.9	11.9	~ 15.4	15.9	~ 19.4	23.9	~ 27.4	31.9 ~	35.4	43.9 ~	47.4	55.9 ~ 59.4	12.4 ~ 14.4	16.4 ~ 18.4	24.4 ~ 26.4
r						•		1.0		•					



# 2.4 Taping (\u00f6330mm Reel) Dry Pack Packing Specifications

- \*1: For a product of witch part number is suffixed with "E1", a " G (R)" marks is display to the moisture barrier bag and the inner boxes.
- \*2: The size of the outer box may be changed depending on the quantity of inner boxes.
- \*3: The space in the outer box will be filled with empty inner boxes, or cushions, etc.
- \*4: Please refer to an attached sheet about the indication label.

Note: The packing specifications may not be applied when the product is delivered via a distributor.

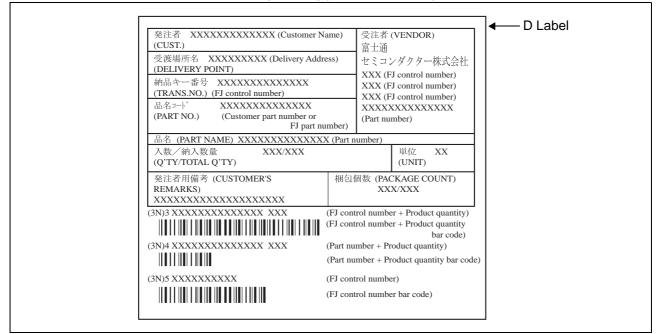


#### 2.5 Product label indicators

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]

XXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXX	C-3 Label
(3N)1 XXXXXXXXXXXX XXX (LEAD FREE mark) (Part number and quantity) QC PASS	
(3N)2 XXXXXXXX XXXXXXXXXXXXXXXXXXXXXXXXXXX	
XXX pcs (Quantity) XXXXXXXXXXXXXXXX (Customer part number or FJ part number)	
bar code) XXXX/XX/XX (Packed years/month/day) ASSEMBLED IN xxxx	Perforated line
XXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXX	Supplemental Label
XXXXXXXXXX (FJ control number ) (Lot Number and quantity) XXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXX	

Label II-A: Label on Outer box [D Label] (100mm × 100mm)



#### Label II-B: Outer boxes product indicate

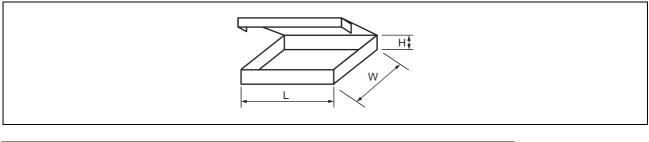
XXXXXXXXXXXXXXXX	(Part number)		
(Lot Number) XXXX-XXX XXXX-XXX	(Count) X箱 X箱 計	(Quantity) XXX 個 XXX 個 XXX 個	

Note: Depending on shipment state, "Label II-A" and "Label II-B" on the external boxes might not be printed.

Г

# 2.6 Dimensions for Containers

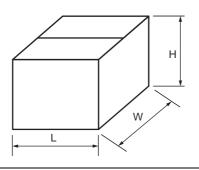
#### (1) Dimensions for inner box



Tape width	L	W	Н
12, 16	365	345	40
24, 32			50
44			65
56			75

(Dimensions in mm)

# (2) Dimensions for outer box



L	W	Н
415	400	315

(Dimensions in mm)

# ■ MAJOR CHANGES IN THIS EDITION

A change on a page is indicated by a vertical line drawn on the left side of that page.

Page	Section	Change Results
16	■ NOTE ON USE	Revised the following description. "Data written before performing IR reflow is not guaranteed af- ter IR reflow." →"We recommend programming of the device after reflow. Data written before reflow cannot be guaranteed."
18	■ REFLOW CONDITIONS AND FLOOR LIFE	Revised to following description. [ JEDEC MSL ] : Moisture Sensitivity Level 3 (ISP/JEDEC J- STD-020D)
	■ CURRENT STATUS ON CONTAINED RESTRICTED SUBSTANCES	Changed the title and revised the description which refers to a website.
19	■ ORDERING INFORMATION	Changed the Minimum shipping quantity. $1 \rightarrow$ * Added the following note below table. *: Please contact our sales office about minimum shipping quantity.
23	1.2 Tube Dry pack packing specifications	Changed the location of humidity indicator.



# FUJITSU SEMICONDUCTOR LIMITED

Nomura Fudosan Shin-yokohama Bldg. 10-23, Shin-yokohama 2-Chome, Kohoku-ku Yokohama Kanagawa 222-0033, Japan http://jp.fujitsu.com/fsl/en/

For further information please contact:

#### North and South America

FUJITSU SEMICONDUCTOR AMERICA, INC. 1250 E. Argues Avenue, M/S 333 Sunnyvale, CA 94085-5401, U.S.A. Tel: +1-408-737-5600 Fax: +1-408-737-5999 http://us.fujitsu.com/micro/

#### Europe

FUJITSU SEMICONDUCTOR EUROPE GmbH Pittlerstrasse 47, 63225 Langen, Germany Tel: +49-6103-690-0 Fax: +49-6103-690-122 http://emea.fujitsu.com/semiconductor/

#### Korea

FUJITSU SEMICONDUCTOR KOREA LTD. 902 Kosmo Tower Building, 1002 Daechi-Dong, Gangnam-Gu, Seoul 135-280, Republic of Korea Tel: +82-2-3484-7100 Fax: +82-2-3484-7111 http://www.fujitsu.com/kr/fsk/

#### Asia Pacific

FUJITSU SEMICONDUCTOR ASIA PTE. LTD. 151 Lorong Chuan, #05-08 New Tech Park 556741 Singapore Tel: +65-6281-0770 Fax: +65-6281-0220 http://sg.fujitsu.com/semiconductor/

FUJITSU SEMICONDUCTOR SHANGHAI CO., LTD. 30F, Kerry Parkside, 1155 Fang Dian Road, Pudong District, Shanghai 201204, China Tel: +86-21-6146-3688 Fax: +86-21-6146-3660 http://cn.fujitsu.com/fss/

FUJITSU SEMICONDUCTOR PACIFIC ASIA LTD. 2/F, Green 18 Building, Hong Kong Science Park, Shatin, N.T., Hong Kong Tel: +852-2736-3232 Fax: +852-2314-4207 http://cn.fujitsu.com/fsp/

#### All Rights Reserved.

FUJITSU SEMICONDUCTOR LIMITED, its subsidiaries and affiliates (collectively, "FUJITSU SEMICONDUCTOR") reserves the right to make changes to the information contained in this document without notice. Please contact your FUJITSU SEMICONDUCTOR sales representatives before order of FUJITSU SEMICONDUCTOR device. Information contained in this document, such as descriptions of function and application circuit examples is presented solely for reference to examples of operations and uses of FUJITSU SEMICONDUCTOR device. FUJITSU SEMICONDUCTOR disclaims any and all warranties of any kind, whether express or implied, related to such information, including, without limitation, quality, FUJITSU SEMICONDUCTOR device based on such information, you must assume any responsibility or liability arising out of or in connection with such information or any use thereof. FUJITSU SEMICONDUCTOR assumes no responsibility or liability for any damages whatsoever arising out of or in connection with such information or any use thereof.

Nothing contained in this document shall be construed as granting or conferring any right under any patents, copyrights, or any other intellectual property rights of FUJITSU SEMICONDUCTOR or any third party by license or otherwise, express or implied. FUJITSU SEMICONDUCTOR assumes no responsibility or liability for any infringement of any intellectual property rights or other rights of third parties resulting from or in connection with the information contained herein or use thereof.

The products described in this document are designed, developed and manufactured as contemplated for general use including without limitation, ordinary industrial use, general office use, personal use, and household use, but are not designed, developed and manufactured as contemplated for general use including manufactured as contemplated (1) for use accompanying fatal risks or dangers that, unless extremely high levels of safety is secured, could lead directly to death, personal injury, severe physical damage or other loss (including, without limitation, use in nuclear facility, aircraft flight control system, air traffic control system, mass transport control system, medical life support system and military application), or (2) for use requiring extremely high level of reliability (including, without limitation, submersible repeater and artificial satellite). FUJITSU SEMICONDUCTOR shall not be liable for you and/or any third party for any claims or damages or damag

arising out of or in connection with above-mentioned uses of the products. Any semiconductor devices fail or malfunction with some probability. You are responsible for providing adequate designs and safeguards against injury, damage or loss from such failures or malfunctions, by incorporating safety design measures into your facility, equipments and products such as redundancy, fire protection, and prevention of overcurrent levels and other abnormal operating conditions. The products and technical information described in this document are subject to the Foreign Exchange and Foreign Trade Control

Law of Japan, and may be subject to export or import laws or regulations in U.S. or other countries. You are responsible for ensuring compliance with such laws and regulations relating to export or re-export of the products and technical information described herein. All company names, brand names and trademarks herein are property of their respective owners.

Edited: Corporate Planning Department